

SN54HCT125, SN74HCT125 QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS

SCLS069B – NOVEMBER 1988 – REVISED MARCH 1996

- Inputs Are TTL-Voltage Compatible
- High-Current 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

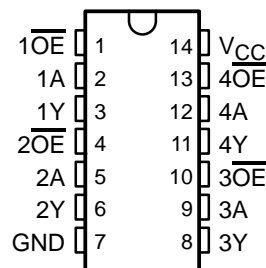
These bus buffer gates feature independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable (\overline{OE}) input is high.

The SN54HCT125 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74HCT125 is characterized for operation from -40°C to 85°C .

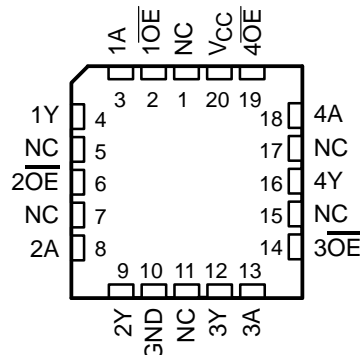
FUNCTION TABLE
(each gate)

INPUTS		OUTPUT
\overline{OE}	A	Y
L	H	H
L	L	L
H	X	Z

SN54HCT125 . . . J OR W PACKAGE
SN74HCT125 . . . D OR N PACKAGE
(TOP VIEW)

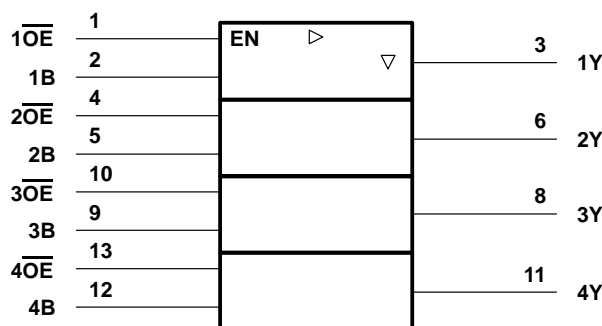


SN54HCT125 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.



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TEXAS
INSTRUMENTS

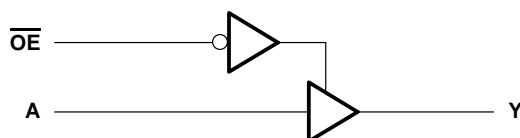
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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V_{CC} or GND	±70 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 2):	
D package	1.25 W
N package	1.1 W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

recommended operating conditions

		SN54HCT125			SN74HCT125			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	$V_{CC} = 4.5\text{ V to }5.5\text{ V}$		2	2			V
V_{IL}	Low-level input voltage	$V_{CC} = 4.5\text{ V to }5.5\text{ V}$		0	0		0.8	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
t_t	Input transition (rise and fall) time	0		500	0		500	ns
T_A	Operating free-air temperature	–55		125	–40		85	°C

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C			SN54HCT125		SN74HCT125		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	V _I = V _{IH} or V _{IL}	4.5 V	I _{OH} = -20 µA			4.4	4.499	4.4	4.4	V
			I _{OH} = -6 mA			3.98	4.3	3.7	3.84	
V _{OL}	V _I = V _{IH} or V _{IL}	4.5 V	I _{OL} = 20 µA			0.001	0.1	0.1	0.1	V
			I _{OL} = 6 mA			0.17	0.26	0.4	0.33	
I _I	V _I = V _{CC} or 0	5.5 V	±0.1	±100		±1000		±1000		nA
I _{OZ}	V _O = V _{CC} or 0, V _I = V _{IH} or V _{IL}	5.5 V	±0.01	±0.5		±10		±5		µA
I _{CC}	V _I = V _{CC} or 0, I _O = 0	5.5 V		8		160		80		µA
ΔI _{CC} †	One input at 0.5 V or 2.4 V, Other inputs at 0 or V _{CC}	5.5 V	1.4	2.4		3		2.9		mA
C _i		4.5 V to 5.5 V	3	10		10*		10		pF

* On products compliant to MIL-STD-883C, Class B, this parameter is not production tested.

† This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 or V_{CC}.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HCT125		SN74HCT125		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	4.5 V		15	26		39		33	ns
			5.5 V		12	23		35		30	
t _{en}	$\overline{\text{OE}}$	Y	4.5 V		18	28		42		35	ns
			5.5 V		15	25		38		31	
t _{dis}	$\overline{\text{OE}}$	Y	4.5 V		15	26		39		33	ns
			5.5 V		13	23		35		30	
t _t		Any	4.5 V		8	15		22		19	ns
			5.5 V		7	14		21		17	

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HCT125		SN74HCT125		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	4.5 V		19	36		58		46	ns
			5.5 V		16	32		48		42	
t _{en}	$\overline{\text{OE}}$	Y	4.5 V		25	40		60		50	ns
			5.5 V		21	35		53		43	
t _t		Any	4.5 V		17	42		63		53	ns
			5.5 V		14	38		57		48	

operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load	35	pF

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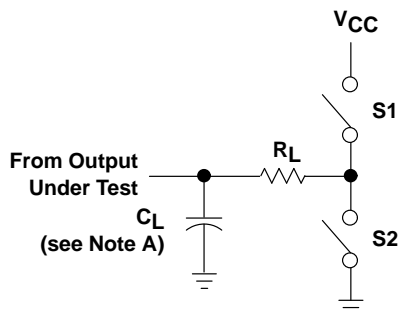


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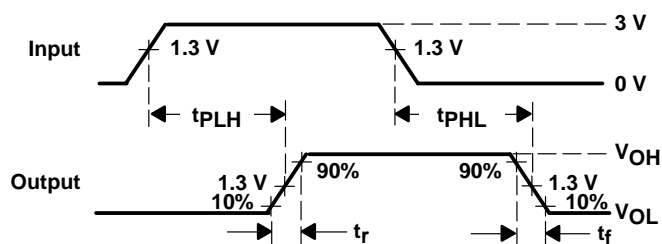
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PARAMETER MEASUREMENT INFORMATION

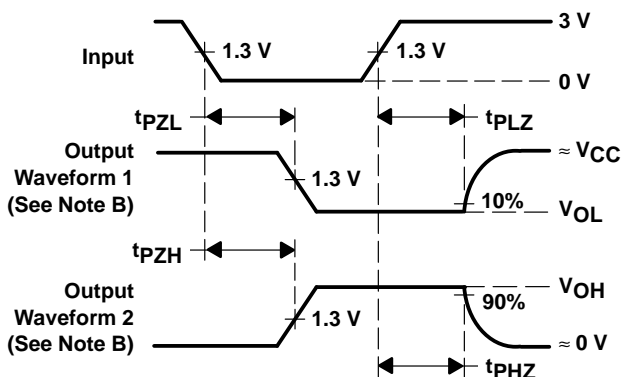


LOAD CIRCUIT

PARAMETER	R_L	C_L	S1	S2
t_{en}	1 k Ω	50 pF or 150 pF	Open	Closed
			Closed	Open
t_{dis}	1 k Ω	50 pF	Open	Closed
			Closed	Open
t_{pd} or t_t	—	50 pF or 150 pF	Open	Open



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1$ MHz, $Z_O = 50 \Omega$, $t_r = 6$ ns, $t_f = 6$ ns.
 - The outputs are measured one at a time with one input transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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